

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	8634	(data with (select selecting selection) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L15	1126	((sample specimen wafer die) with (matrix array) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L16	183	((pca (principal adj component adj analysis)) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L17	81	(model with maintenance with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L18	537	((product sample specimen wafer die defect error fault) with (classing classifying classification categorizing categorize category categorization) with (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L19	66	l14 and l15	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L20	12	l14 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L21	15	l14 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L22	45	l14 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L23	30	l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L24	0	l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L25	6	l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L26	0	l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L27	1	l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L28	2	l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L29	1	l14 and l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22

L30	0	l14 and l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L31	1	l14 and l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L32	0	l14 and l15 and l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L33	0	l14 and l15 and l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L34	0	l14 and l15 and l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L35	1454	((data near3 (select selecting selection) near3 (module routine sub\$routine)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L36	167	((sample specimen wafer die) near3 (matrix array) near3 (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L37	48	((pca (principal adj component adj analysis)) near3 (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L38	11	(model near3 maintenance near3 (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L39	125	((product sample specimen wafer die defect error fault) near3 (classing classifying classification categorizing categorize category categorization) near3 (module routine sub\$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:26
L40	1	l35 and l36	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L41	0	l35 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L42	0	l35 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L43	2	l35 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L44	0	l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L45	0	l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L46	0	l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27

L47	0	137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L48	0	137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L49	2	138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:31
L50	0	135 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L51	0	135 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L52	0	135 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L53	0	135 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L54	0	135 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L55	0	135 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L56	0	135 and 136 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L57	0	135 and 136 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L58	0	135 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L59	0	135 and 136 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L60	352656	(industrial manufacturing plasma etch etching) near3 process	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L61	93	160 and 135	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L62	49	160 and 136	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L63	6	160 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32

L64	3	160 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L65	36	160 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L66	0	160 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L67	0	160 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L68	0	160 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L69	0	160 and 135 and 136	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L70	0	160 and 135 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L71	0	160 and 135 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L72	0	160 and 135 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L73	0	160 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L74	0	160 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L75	2	160 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L76	0	160 and 135 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L77	0	160 and 135 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L78	0	160 and 135 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L79	0	160 and 135 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L80	0	160 and 135 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34

L81	0	160 and 135 and 136 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L82	0	160 and 135 and 136 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L83	0	160 and 135 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L84	0	160 and 135 and 136 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L85	0	160 and 135 and 136 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
S1	10	("5658423" "5864773" "6153115" "6192826" "6419846" "6442445" "6521080" "20020104832" "20020119668" "20030055523").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/21 10:31
S2	2318	principal adj component adj analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 06:50
S3	271	(principal adj component adj analysis) and ((industrial or plasma or manufacturing) adj process)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/21 10:33
S4	677	(principal adj component adj analysis) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomaly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S5	157	S4 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15
S6	104	S5 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S7	2447	(principal adj component) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomaly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15

S8	369	S7 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S9	195	S8 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:17
S10	162	S9 and (compute computing computation calculate or claculating calculation calculable computed calculated) and (category catagorizing catagorized sort sorted sorting correlate correlated correlating correlation collate collating collated collation)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:25
S11	102	S10 and (residue residual)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:26
S12	101	S11 and (single singular)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:28
S13	97	S12 and (matrix array matrices)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:34
S14	81	S13 and vector	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:41
S15	11	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:50
S16	59	("5658423").URPN.	USPAT	OR	OFF	2004/12/23 10:55
S17	9	("5121337" "5288367" "5479340" "5552016" "5658423" "5862060" "5885472" "6060328" "6153115").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:56
S18	11	("6238937").URPN.	USPAT	OR	OFF	2004/12/23 10:57
S19	9	("5121337" "5288367" "5479340" "5658423" "5862060" "5885472" "6060328" "6153115" "6238937").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:57
S20	7	("5121337" "5288367" "5479340" "5658423" "5862060" "6238937" "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S21	1	("6564114").URPN.	USPAT	OR	OFF	2004/12/23 10:58
S22	9	("5121337" "5288367" "5479340" "5658423" "5862060" "6153115" "6238937" "6368879" "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S23	0	("6582618").URPN.	USPAT	OR	OFF	2004/12/23 10:50
S24	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51

S25	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S13	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51
S26	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S12	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S27	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S11	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S28	0	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S10	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S29	1	("4888199" "5014217" "5040734" "5114233" "5121337" "5172312" "5288367" "5308414" "5347460" "5442562" "5467883").PN. and S9	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S30	6	("5658423").URPN. and S14	USPAT	OR	ON	2004/12/23 10:55
S31	1	("5121337" "5288367" "5479340" "5552016" "5658423" "5862060" "5885472" "6060328" "6153115").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:56
S32	3	("6238937").URPN. and S14	USPAT	OR	ON	2004/12/23 10:57
S33	2	("5121337" "5288367" "5479340" "5658423" "5862060" "5885472" "6060328" "6153115" "6238937").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:57
S34	3	("5121337" "5288367" "5479340" "5658423" "5862060" "6238937" "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:59
S35	0	("6564114").URPN. and S14	USPAT	OR	ON	2004/12/23 10:58
S36	3	("5121337" "5288367" "5479340" "5658423" "5862060" "6153115" "6238937" "6368879" "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:03
S37	7	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423").PN. and S14	USPAT	OR	ON	2004/12/23 11:12
S38	320	438/5.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:22
S39	558	700/90.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S40	448	700/95.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S41	467	700/108.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13

S42	236	700/109.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S43	319	700/110.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S44	448	700/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S45	1131	700/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S46	499	702/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S47	211	702/118.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S48	104	702/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S49	839	702/182.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S50	676	702/183.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S51	372	702/185.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S52	516	702/189.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S53	58	702/196.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S54	218	438/8.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S55	251	438/9.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S56	96	438/5.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S57	80	438/8.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23

S58	97	438/9.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S59	28	700/90.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S60	75	700/95.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S61	155	700/108.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S62	90	700/109.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S63	98	700/110.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S64	74	700/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S65	281	700/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S66	23	702/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S67	19	702/118.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S68	8	702/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S69	149	702/182.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S70	133	702/183.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25

S71	71	702/185.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S72	59	702/189.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S73	5	702/196.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S74	4	S56 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S75	4	S57 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S76	0	S56 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S77	1	S57 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S78	5	S58 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S79	0	S59 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S80	0	S60 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S81	1	S61 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S82	0	S62 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S83	1	S63 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S84	1	S64 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S85	3	S65 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S86	0	S66 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28

S87	0	S67 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S88	0	S68 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S89	0	S69 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S90	1	S70 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S91	0	S71 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S92	0	S72 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S93	0	S73 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S94	14	("5130936" "5133046" "5148378" "5237518" "5267277" "5465321" "5548378" "5629872" "5642296" "5661666" "5680409" "5715178" "5726915" "6219626").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 11:32
S95	4	("6415276").URPN.	USPAT	OR	OFF	2004/12/23 11:35
S96	10	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423" "6415276" "20030109951").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:47
S97	158	jahns.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S98	0	jahns-gary.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S99	0	zhang-y.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S100	0	palladino-a.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S101	69	palladino.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S102	8231	zhang.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S103	0	zhang-yixin.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S104	0	palladino-anthony.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S105	57	(jahns zhang palladino).in. and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT	OR	ON	2004/12/29 09:50
S106	1	"5711843".pn.	USPAT	OR	OFF	2004/12/23 11:56

S107	92	((industrial or manufacturing or production or plasma) near3 process) and ((fault or flaw or defect or malfunction) near4 (detect\$3 or determin\$5 or discover\$3)) and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 09:56
S108	16697	((process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:28
S109	107	S108 and (pca (principal adj component adj analysis))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:27
S110	313	((industrial manufacturing plasma etching) near3 (process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 06:43
S111	30	(pca (principal adj component adj analysis)) and (((industr\$3 manufactur\$3 assembl\$3 produc\$4) near3 (process procedure)) with (defect\$3 fault flaw error malfunction\$3) with (detect\$3 determin\$5 locat\$3 find\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 08:18
S112	5	("6521080" "6368975" "5864773" "5658423" "20030136511").pn.	US-PGPUB; USPAT	OR	ON	2004/12/30 07:09
S113	21	("5274572" "5305221" "5319580" "5386373" "5406502" "5453156" "5459668" "5465321" "5479340" "5486995" "5526293" "5528510" "5548528" "5566092" "5570300" "5642296" "5646870" "5655110" "5658423" "5659467" "5680409").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S114	28	("5864773").URPN.	USPAT	OR	OFF	2004/12/30 07:17
S115	6	("4312732" "5653894" "5711843" "5885472" "5966586" "6017414").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S116	3	("6368975").URPN.	USPAT	OR	OFF	2004/12/30 07:18
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2 A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes
Yang Yinghua; Lu Ningyun; Wang Fuli; Ma Liling;

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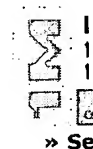
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7 A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes

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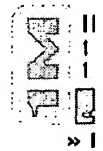
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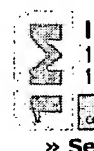
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1 Fusion of fuzzy/neuro/evolutionary computing for knowledge acquisition
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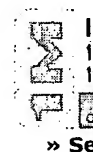
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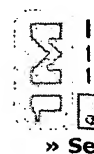
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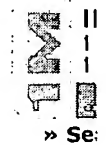
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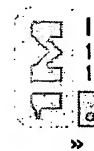
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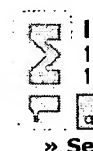
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